

PTO/SB/08a/b (08-03)

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Substitute for form 1449A/B/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)				<b>Complete if Known</b>	
				Application Number	10/807,537
				Filing Date	March 23, 2004
				First Named Inventor	Yehuda Shekel
				Art Unit	<del>NA</del> 1763
				Examiner Name	<del>Not Yet Assigned</del> Culbert
Sheet	1	of	2	Attorney Docket Number	06727/0201090-USO

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
RC	AA**	US-5,376,214-B1	12/1994	Iwasaki, et al.	
	AB**	US-6,270,986-B1	08/2001	Wong	
	AC**	US-5,893,046-B1	04/1999	Wu, et al.	
	AD**	US-5,938,885-B1	08/1999	Huang, et al.	
	AE**	US-5,830,375-B1	11/1998	Huang, et al.	
	AF**	US-5,778,801-B1	08/1998	Barbee, et al.	
	AG**	US-5,582,746-B1	12/1996	Barbee, et al.	
	AH**	US-5,500,073-B1	03/1996	Barbee, et al.	
	AI**	US-5,694,207-B1	12/1997	Huang, et al.	
	AJ**	US-5,573,624-B1	11/1996	Barbee, et al.	
	AK**	US-5,573,623-B1	11/1996	Barbee, et al.	
	AL**	US-5,516,399-B1	05/1996	Balconi-Lamica, et al.	
	AM**	US-5,450,205-B1	09/1995	Sawin, et al.	
	AN**	US-5,392,124-B1	02/1995	Barbee, et al.	
	AO**	US-5,337,144-B1	08/1994	Strul, et al.	
	AP**	US-5,097,130-B1	03/1992	Koashi, et al.	
	AQ**	US-4,710,261-B1	12/1987	Dennis	
	AR**	US-4,454,001-B1	06/1984	Sternheim, et al.	
	AS**	US-4,060,097-B1	11/1977	Oxford	
✓	AT**	US-6,013,165-B1	01/2000	Wiktorowicz, et al.	
RC	AU**	US-6,203,659-B1	03/2001	Shen, et al.	

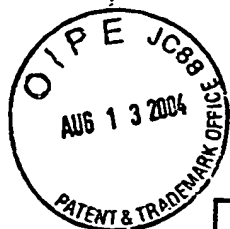
\*\* Pursuant to the Notice issued by the United States Patent and Trademark Office dated July 11, 2003 waiving the requirements of 37 C.F.R. § 1.98(a)(2)(i), a copy/copies of the United States Patent on PTO/SB08 is/are not being submitted.

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
RC	CA	De Keersmacker, R., Dielectric Breakdown in Thermally Growing Oxide Layer, Chapter 7, Katolieke Universiteit Leuven, Belgium 1993.	
RC	CB	Judge, John S., "A Study of the Dissolution of SiO <sub>2</sub> in Acidic Fluoride Solutions", J. Electrochem. Soc., November 1971, pp. 1772-1775.	

Examiner Signature	/Roberts Culbert/	Date Considered	05/30/2006
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				Examiner Name	<del>Not Yet Assigned</del> Culbert
Sheet	2	of	2	Attorney Docket Number	06727/0201090-USO

RC	CC	Moore, Walter J., "Physical Chemistry", 4th Edition, Longmans, 1963.	
	CD	Carpio, Ronald, et al., "Concentration Control of SC-1 Megasonic Processing Baths", Electrochemical Society Proceedings (1994), Vol. 4, Section III, pp. 253-266.	
	CE	Burns, Donald, et al., ed., "Handbook of Near-Infrared Analysis", Marcel Dekker Inc., 1992.	
	CF	Kashkoush, Ismail, et al., "In-Situ Chemical Concentration Control for Wafer Wet Cleaning", Mat. Res. Soc. Symp. Proc. (1997), Vol. 477, p. 311-316.	
	CG	Fischer, Wolfgang B., et al., "Corrections to the Baseline Distortions in the OH-Stretch Region of Aqueous Solutions", Appl. Spec. 1994, Vol. 48 (1), pp. 107-112.	
RC	CH	Thompson, Christopher J., et al., "Quantification of Hydrofluoric Acid Species by Chemical-Modeling Regression of Near-Infrared Spectra", Anal. Chem. 1997, Vol. 69, pp. 25-35.	

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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